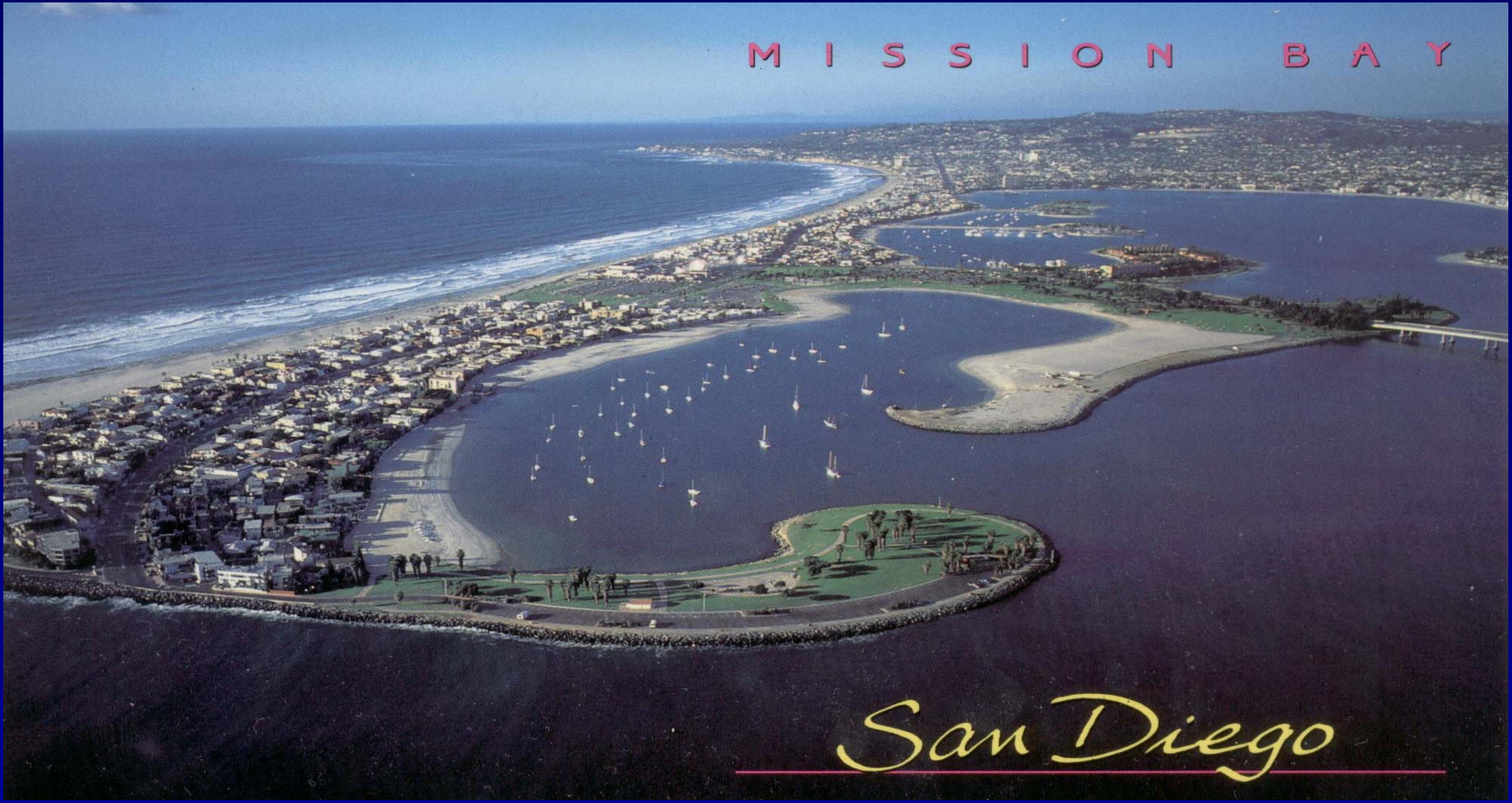
SOUTHWEST TEST WORKSHOP

- To Advance Wafer Test Technology
- To Serve and Inform the Wafer Test Professional
- To Boldly Go Where No Workshop Has Gone Before

San Diego, CA, June 6 to 9, 2004

WELCOME TO SAN DIEGO



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WHAT IS SWTW 2004?

- “THE” Conference for Wafer Test Professionals
- Not a theoretical or academic conference
- Not a Sales Show
- It’s a *Probe Technology Forum*
- Provides practical solutions to real problems
- Mixture of vendor and user presentations
- Informal and relaxed atmosphere

INFORMAL CONFERENCE

- **Long Breaks**
- **Plenty of networking opportunities**
- **Informal discussions**
- **Numerous social activities**
- **Meet new people & *<u>have some fun!</u>***

(Don’t tell the IEEE about the fun part)

SWTW – 2004 COMMITTEE

- **Organization and Technical Program**
  - William Mann, SWTW General Chair
  - Jerry Broz, Ph.D., International Test Solutions, Program Chair
  - Maddie Harwood, CEM Inc, Registration and Finance Chair

- **Technical Committee and Session Chairs**
  - Michael Egloff, AMD
  - Michael Harris, Texas Instruments
  - Ken Karklin, Agilent Technologies
  - Ger Koch, Philips Semiconductor
  - Rey Rincon, Kulicke and Soffa
  - Phil Seitzer, Agere Systems
  - Roger Sinsheimer, Xandex
  - Tim Swettlen, Intel
  - Fred Taber, IBM (Retired)
  - Bill Williams, Motorola

TECHNICAL PROGRAM

- **Sunday, June 6, 2004**
  - Tutorials: The Leading Edge of Wafer Test Technology
  - SEMATECH's Best Practices for Probe Card Tracking Systems
  - Keynote Speaker – Steve Strauss, Intel

  "The Impact of Globalization in the Development of the Test Tooling Industry"

TECHNICAL PROGRAM

- **Monday, June 7, 2004**
  - Memory Probing
  - High Power Testing
  - Lunch
  - Micro-Electronic Machine Technologies
  - Low-K Dielectrics and Reduced Force Probe

SOUTHWEST TEST WORKSHOP

TECHNICAL PROGRAM

- Tuesday, June 8, 2004
  - Probe Card Analysis and Troubleshooting
  - Probe Process Characterization
  - Afternoon Social Activities
- Wednesday June 9, 2004
  - Probe Potpourri
  - Challenges, Challenges and More Challenges
  - Best Presentation Awards Luncheon

RECOGNITION & AWARDS

- Best Overall Presentation
- Best Data Presented
- Best Presentation, Tutorial in Nature
- Most “Inspirational” Presentation

- Other “Special Awards”

THE BEST FROM SWTW 2003

- **Bill Williams, Tony Angelo, S. S. Yan, Tu-Anh Tran, Stephen Lee, & Matt Ruston, (Motorola)**

  "44 Micron Pitch Capability Assessment"

- **Tsuyoshi Haga & S. Shimada (Sumitomo Electric Industries)**

  "The New Probe Tip Fabrication by MEMS (LIGA Process) for No-cleaning Test"

- **Cheryl Hatfield (TI), Tom Moore (Omniprobe), & Jerry Broz (Point Technologies)**

  "A Novel In-situ Method to Characterize Bond Pad & Dielectric Deformation for Wafer Level Test"

- **Brett Grossman (Intel) & Bryan Boots (Ansoft)**

  "Predicting Performance of Sort Tooling at 40 GHz"

1st Time EXHIBITS!!!

SV Probe

Applied Precision LLC

Wentworth Laboratories Inc.

Micronics Japan Co., Ltd.

International Test Solutions, Inc.

Point Technologies, Inc.

Electroglas, Inc.

Advanced Probing Systems, Inc.

Pacific Western Systems

JEM America Corp.

International Contact Technologies

Integrated Technology Corporation

Cascade Microtech, Inc

Accretech USA, Inc.

InTest Corp.

FormFactor

Feinmetall GmbH

Test Advantage, Inc.

MicroProbe Inc.

Kulicke & Soffa

Phicom Corp.

Probelogic, Inc.

Eberts Electronic Sales

SigmaProbe

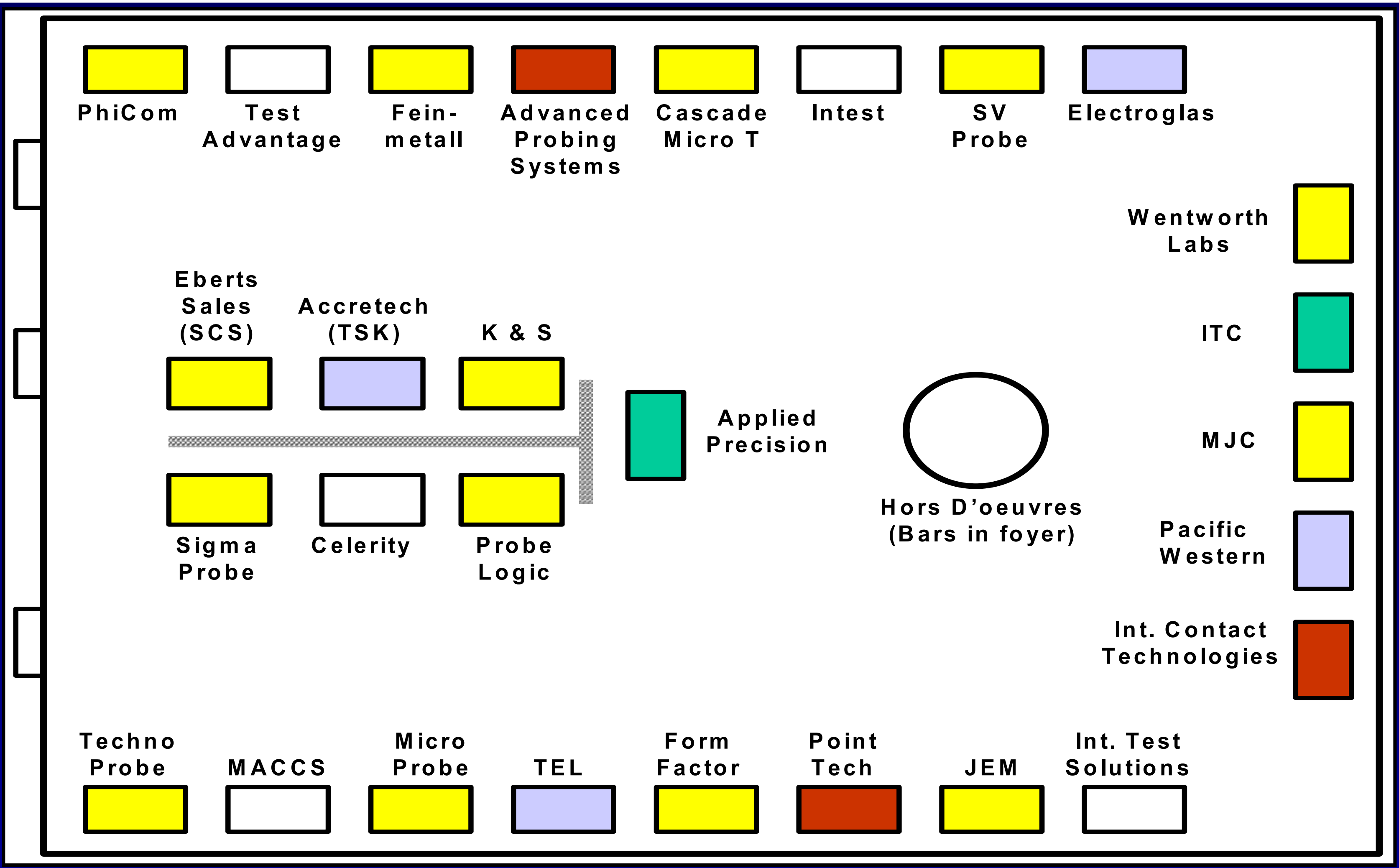
TEL

MACSS

TechnoProbe PBN

Celerity

EXHIBITS FLOORPLAN



PhiCom

Test Advantage

Fein-metall

Advanced Probing Systems

Cascade Micro T

Intest

SV Probe

Electroglas

Wentworth Labs

ITC

MJC

Pacific Western

Int. Contact Technologies

Eberts Sales (SCS)

Accretech (TSK)

K & S

Sigma Probe

Celerity

Probe Logic

Applied Precision

Hors D'oeuvres (Bars in foyer)

Techno Probe

MACCS

Micro Probe

TEL

Form Factor

Point Tech

JEM

Int. Test Solutions

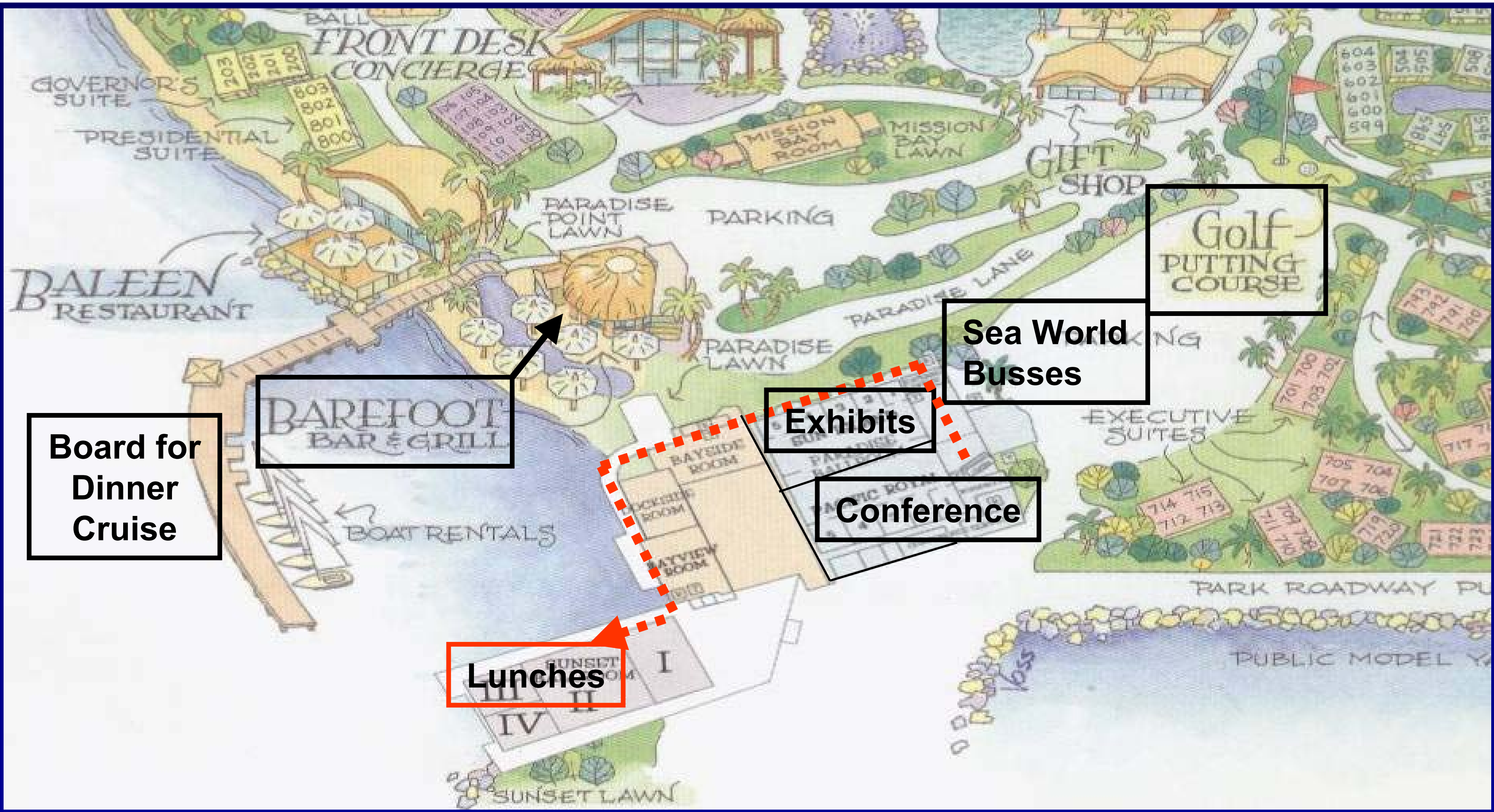
What about the fun part?

- **Monday**
  - **Exhibits Open 4:30 – 6:00 PM**
  - **6:00 Cocktail Reception at the Barefoot Bar**
  - **Team Techno Trivia Contest**
    - **Three (3) individuals per team**
    - **Must be from different companies**
  - **7:00 – 10:00 Sunset Harbor Dinner Cruise**

SOCIAL ACTIVITIES

- Tuesday Afternoon
  - Sea World
  - Miniature Golf
  - Exhibits Open 5:30 – 7:30 PM
  - Cocktail Reception & Hors D'oeuvres
  - Exhibitor's Banquet
  - Let Propulsion Labs: "Mars Exploration"

DON'T GET LOST



Board for Dinner Cruise

Sea World Busses

Exhibits

Conference

Lunches

MARS EXPLORATION

http://www.swtest.org

- Central Online Repository
  - Past presentations
  - Online registration
  - Sign up for our mailing list
  - With more features to come……..
- Tremendous continued success!!
  - Forty eight thousand visits to the site
  - Thanks to “web-efforts” of Jerry Broz

Souvenirs and a “Post Card Home”

“You get to go to San Diego and have a lot of fun……

….. and all I get is this crummy toy!”